

Fig. S1. Diffraction profiles for $Bi_3Nb_{0.8}Yb_{0.2}O_{6.8}$ at room temperature (a) to (c) and $800^{\circ}C$ (d) to (f), fitted by Rietveld analysis, showing neutron back scattering (a) and (d), neutron low angle (b) and (e) and X-ray (c) and (f) data. Observed (+ symbols), calculated (line) and difference (lower) profiles are shown, with reflection positions indicated by markers. Significant superlattice peaks are indicated by an asterisk.

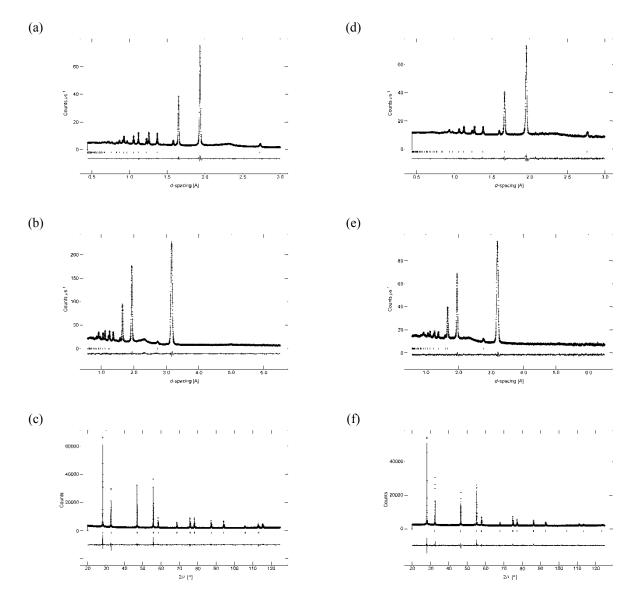


Fig. S2. Diffraction profiles for $Bi_3Nb_{0.6}Yb_{0.4}O_{6.6}$ at room temperature (a) to (c) and 800°C (d) to (f), fitted by Rietveld analysis, showing neutron back scattering (a) and (d), neutron low angle (b) and (e) and X-ray (c) and (f) data. Observed (+ symbols), calculated (line) and difference (lower) profiles are shown, with reflection positions indicated by markers.

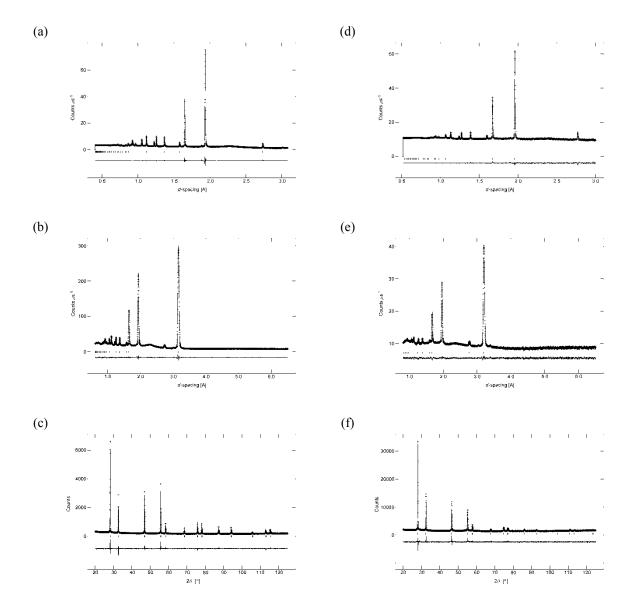


Fig. S3. Diffraction profiles for $Bi_3Nb_{0.4}Yb_{0.6}O_{6.4}$ at room temperature (a) to (c) and $800^{\circ}C$ (d) to (f), fitted by Rietveld analysis, showing neutron back scattering (a) and (d), neutron low angle (b) and (e) and X-ray (c) and (f) data. Observed (+ symbols), calculated (line) and difference (lower) profiles are shown, with reflection positions indicated by markers.